Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	r
10/726,828	TANG ET AL.	
Examiner	Art Unit	
Tan V. Mai	2193	

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Class	Subclass	Date	Examiner	
708	270-277	3/21/2007	MAI	
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nventor(s) search Double Patent Check Data Bases Search (see search istory printout(s))	3/21/2007	MAI
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